

Annex- C

System Performance Check

Measurement Report for Device, , , CW, Channel 0 (450.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 45.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,	CW, 0--		450.000, 0	10.65	0.815	43.1

Hardware Setup

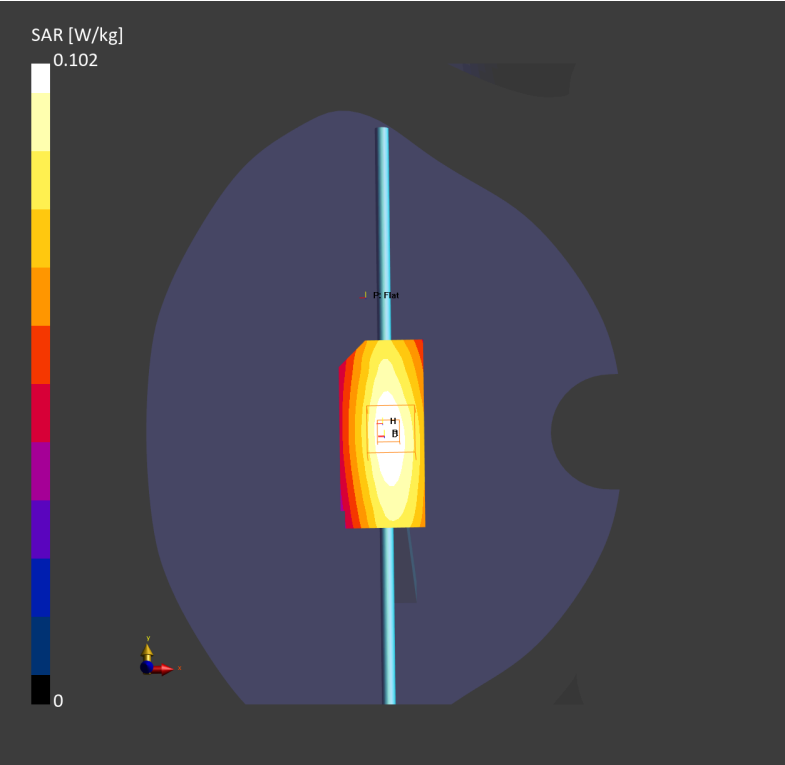
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-04	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-04, 11:10	2025-06-04, 11:15
psSAR1g [W/Kg]	0.098	0.099
psSAR10g [W/Kg]	0.068	0.066
Power Drift [dB]	-0.00	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.0
Dist 3dB Peak [mm]		> 15.0



Pre-Scan – Battery

Body SAR				
Battery	Freq	Output Power (W)	Body SAR 1g(W/Kg)	Body SAR 10g(W/Kg)
BP-283	512	5.058	8.530	6.310
BP-284	512	5.058	8.450	6.160
BP-303	512	5.058	8.290	6.060
BP-305	512	5.058	1.020	0.754

Head SAR				
Battery	Freq	Output Power (W)	Head SAR 1g(W/Kg)	Head SAR 10g(W/Kg)
BP-283	512	5.058	7.100	5.220
BP-284	512	5.058	9.470	6.880
BP-303	512	5.058	7.950	5.850
BP-305	512	5.058	0.999	0.741

Measurement Report for Device, BACK, Custom Band, CW, Channel 512000 (512.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Custom Band	CW, 0--	512.000, 512000	10.65	0.889	41.6

Hardware Setup

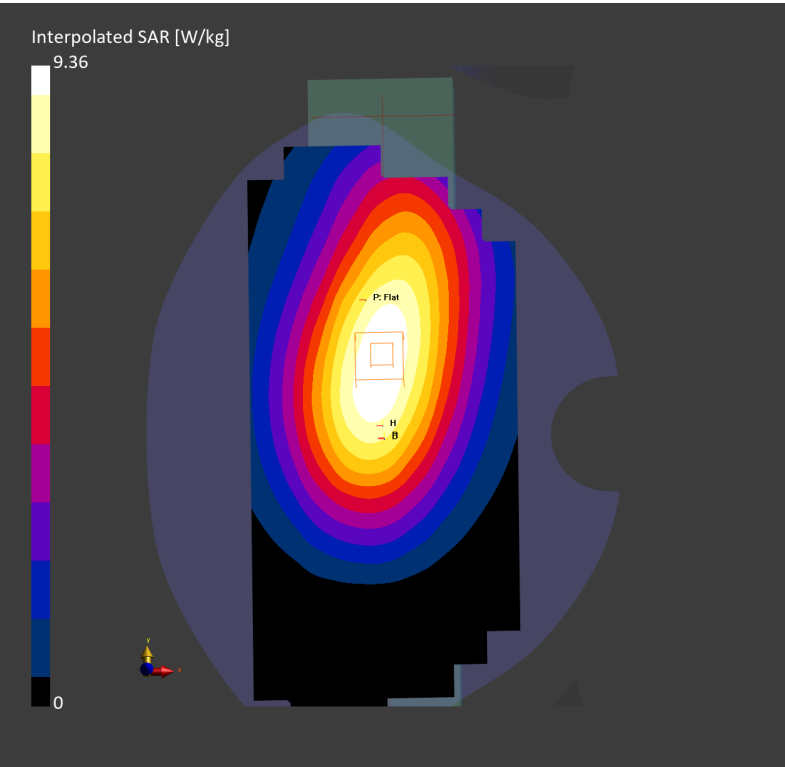
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-05, 15:57	2025-06-05, 16:07
psSAR1g [W/Kg]	8.35	8.53
psSAR10g [W/Kg]	6.05	6.31
Power Drift [dB]	-0.00	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.4
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, BACK, Custom Band, CW, Channel 512000 (512.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Custom Band	CW, 0--	512.000, 512000	10.65	0.889	41.6

Hardware Setup

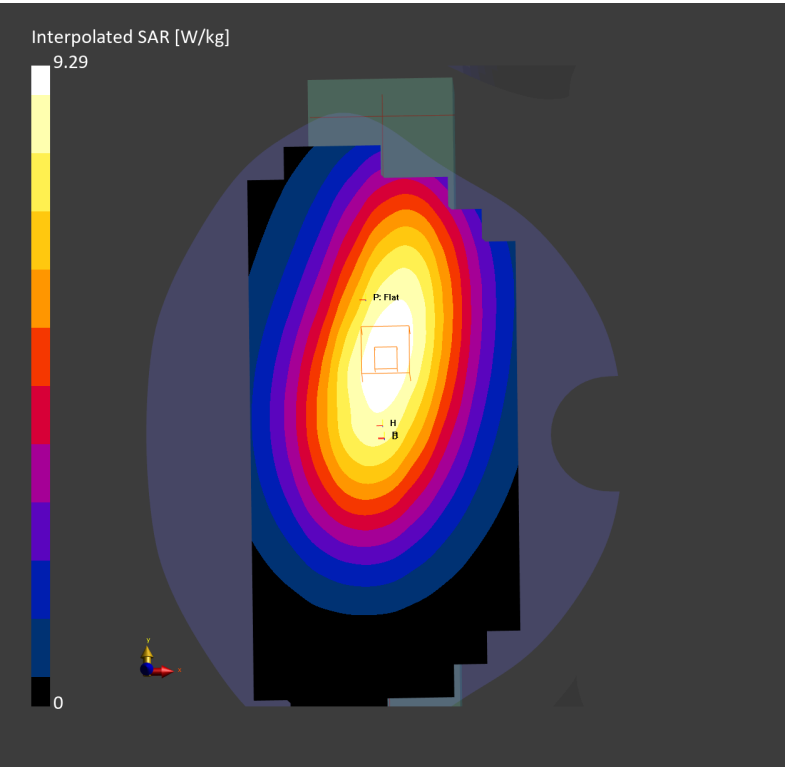
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-05, 16:15	2025-06-05, 16:21
psSAR1g [W/Kg]	8.28	8.45
psSAR10g [W/Kg]	5.98	6.16
Power Drift [dB]	-0.01	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.2
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, BACK, Custom Band, CW, Channel 512000 (512.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Custom Band	CW, 0--	512.000, 512000	10.65	0.889	41.6

Hardware Setup

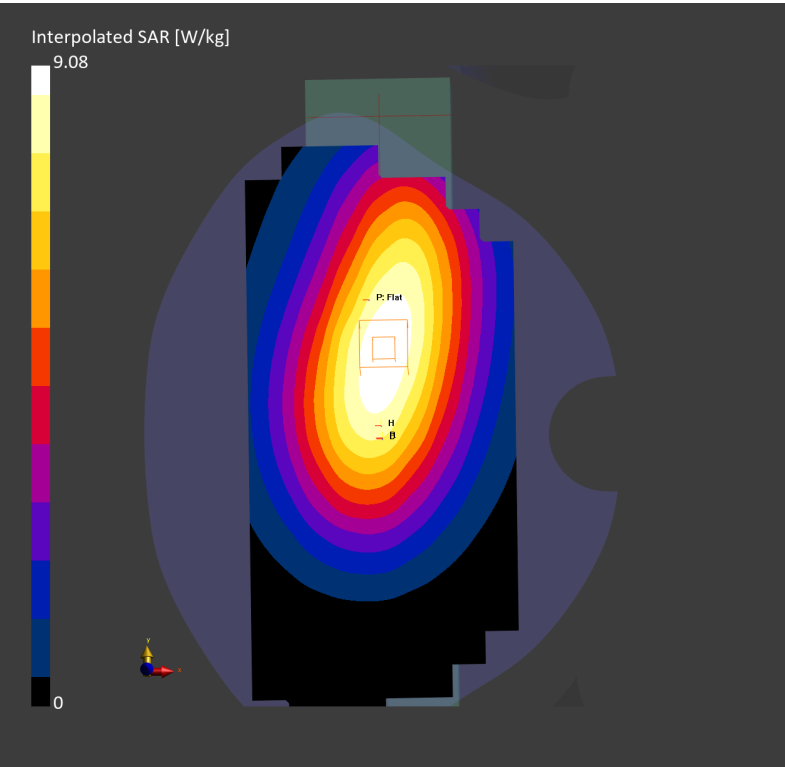
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-05, 16:30	2025-06-05, 16:36
psSAR1g [W/Kg]	8.11	8.29
psSAR10g [W/Kg]	5.86	6.06
Power Drift [dB]	-0.02	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.4
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, BACK, Custom Band, CW, Channel 512000 (512.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Custom Band	CW, 0--	512.000, 512000	10.65	0.889	41.6

Hardware Setup

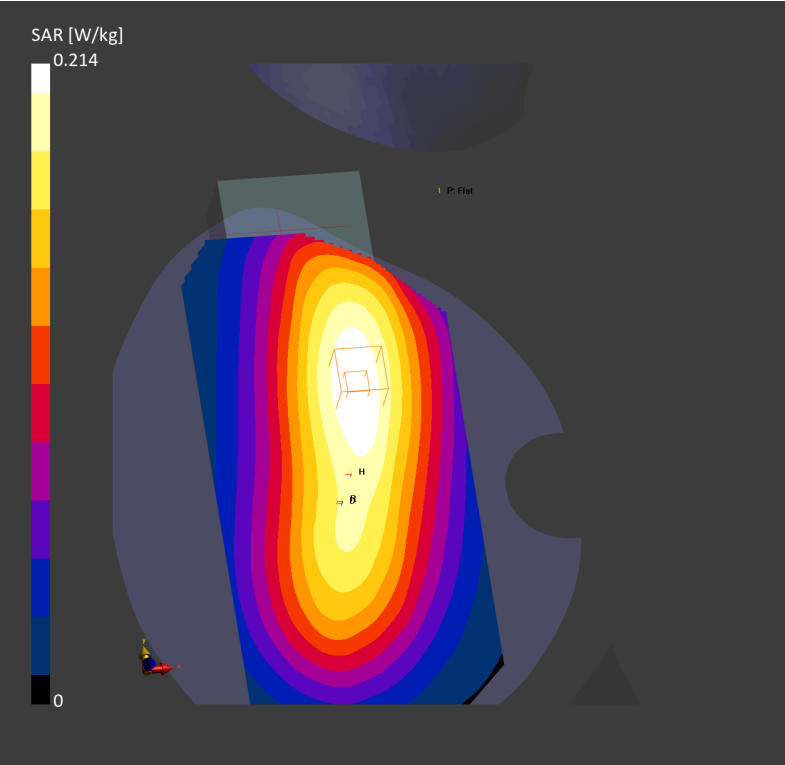
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-05, 11:55	2025-06-05, 12:01
psSAR1g [W/Kg]	0.201	0.207
psSAR10g [W/Kg]	0.146	0.152
Power Drift [dB]	-0.01	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.1
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, FRONT, Custom Band, CW, Channel 512000 (512.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	Custom Band	CW, 0--	512.000, 512000	10.65	0.889	41.6

Hardware Setup

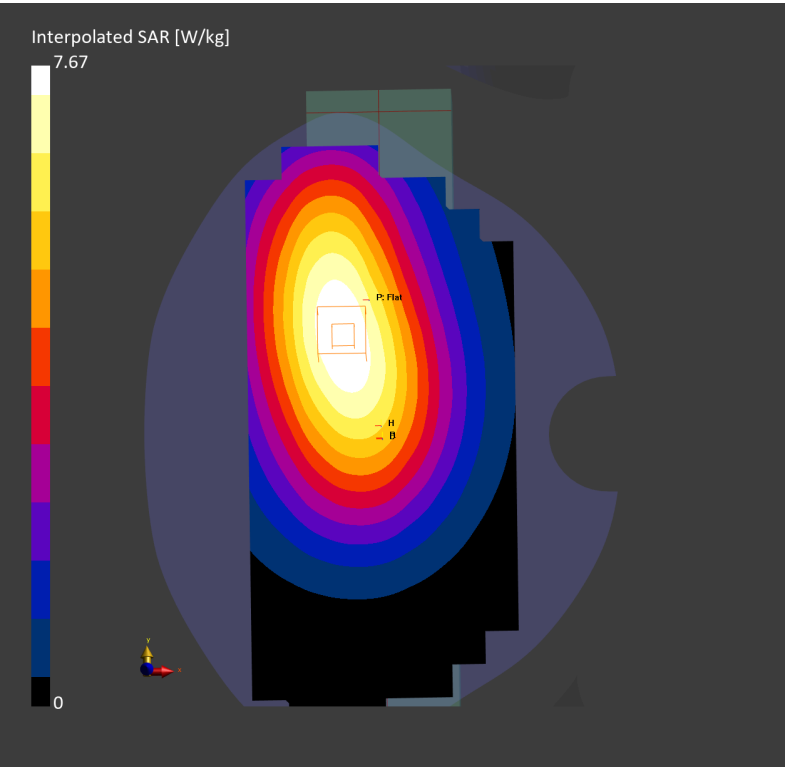
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-05, 16:58	2025-06-05, 17:05
psSAR1g [W/Kg]	6.85	7.10
psSAR10g [W/Kg]	4.96	5.22
Power Drift [dB]	-0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.2
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, FRONT, Custom Band, CW, Channel 512000 (512.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	Custom Band	CW, 0--	512.000, 512000	10.65	0.889	41.6

Hardware Setup

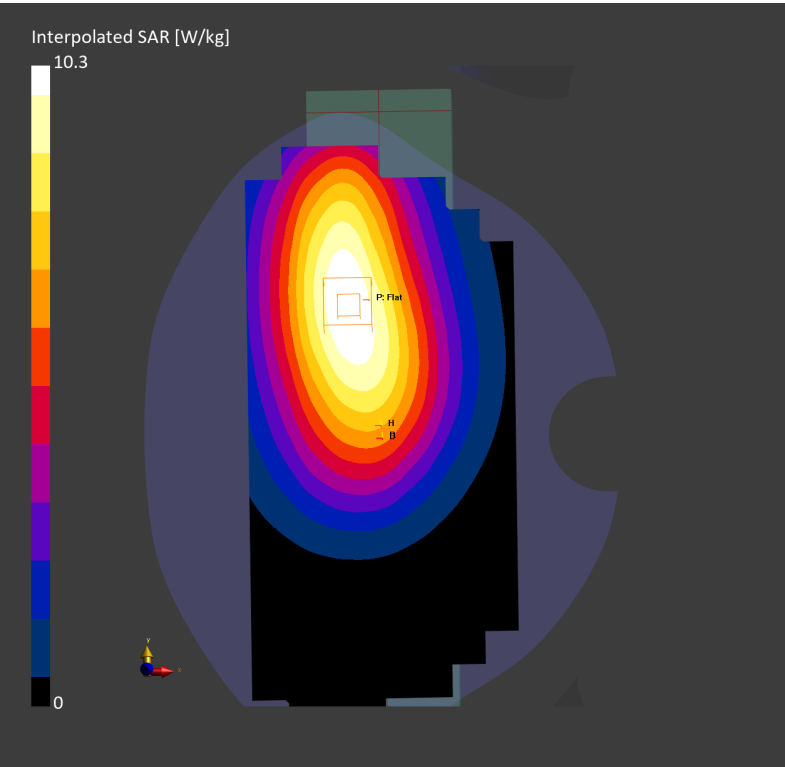
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Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-05, 17:12	2025-06-05, 17:18
psSAR1g [W/Kg]	9.14	9.47
psSAR10g [W/Kg]	6.60	6.88
Power Drift [dB]	-0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.7
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, FRONT, Custom Band, CW, Channel 512000 (512.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	Custom Band	CW, 0--	512.000, 512000	10.65	0.889	41.6

Hardware Setup

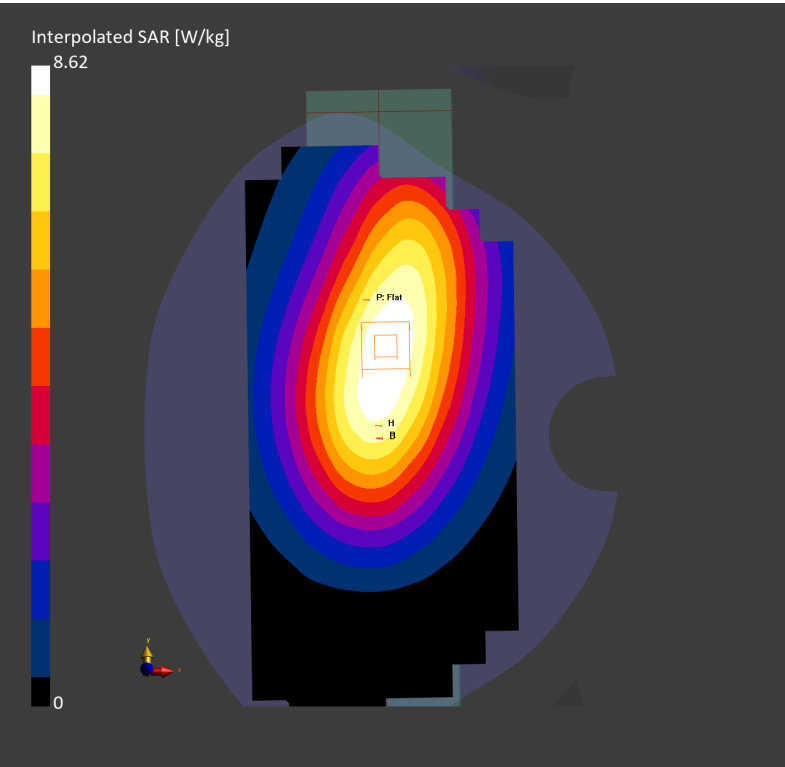
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Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-05, 14:55	2025-06-05, 15:02
psSAR1g [W/Kg]	7.69	7.95
psSAR10g [W/Kg]	5.57	5.85
Power Drift [dB]	-0.00	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.7
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, FRONT, Custom Band, CW, Channel 512000 (512.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	Custom Band	CW, 0--	512.000, 512000	10.65	0.889	41.6

Hardware Setup

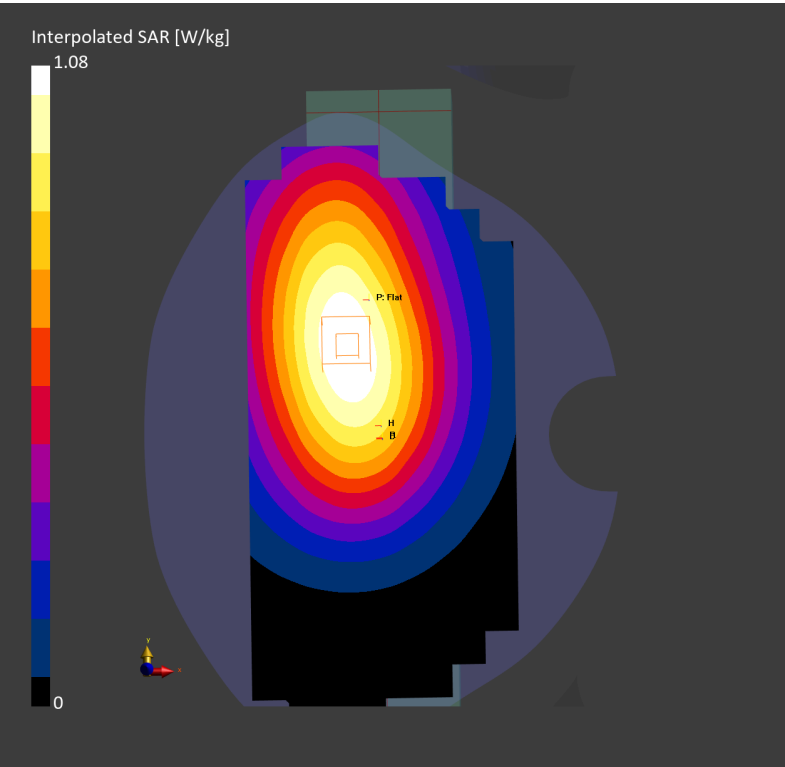
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Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06, 10:11	2025-06-06, 10:17
psSAR1g [W/Kg]	0.965	0.999
psSAR10g [W/Kg]	0.701	0.741
Power Drift [dB]	-0.01	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.4
Dist 3dB Peak [mm]		> 15.0



Belt Clip

Body SAR				
Belt Clip	Output Power (W)	Freq	Body SAR 1g(W/Kg)	Body SAR 10g(W/Kg)
			BP-284	BP-284
			3210mAh	3210mAh
MB-133	5.058	512	8.520	6.250
MB-136	5.058	512	6.280	4.650

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Custom Band	CW, 0--	512.000, 512000	10.65	0.889	41.6

Hardware Setup

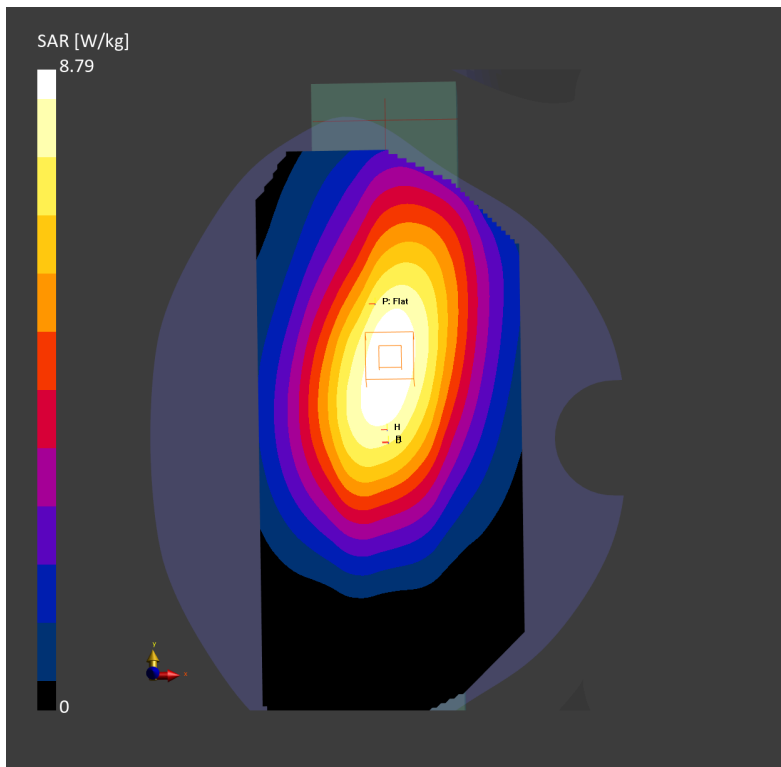
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06, 11:05	2025-06-06, 11:11
psSAR1g [W/Kg]	8.27	8.52
psSAR10g [W/Kg]	6.00	6.25
Power Drift [dB]	-0.00	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.2
Dist 3dB Peak [mm]		> 15.0



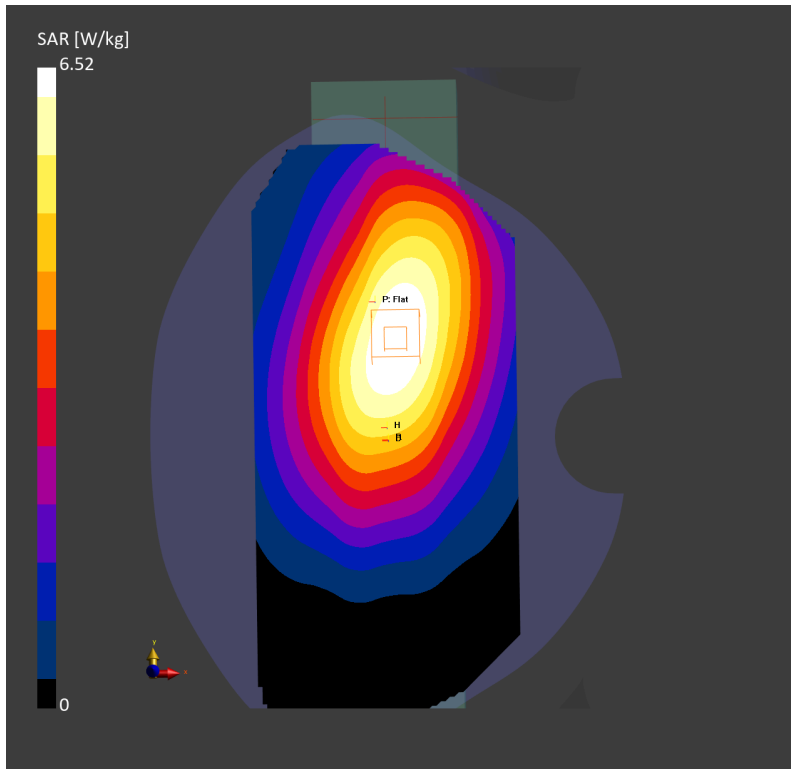
Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Custom Band	CW, 0--	512.000, 512000	10.65	0.889	41.6

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) – 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 – SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-06-06, 11:22	2025-06-06, 11:28
psSAR1g [W/Kg]	6.14	6.28
psSAR10g [W/Kg]	4.47	4.65
Power Drift [dB]	-0.01	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.0
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, FRONT, D400, CW, Channel 100 (450.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	D400	CW, 0--	450.000, 100	10.65	0.833	43.2

Hardware Setup

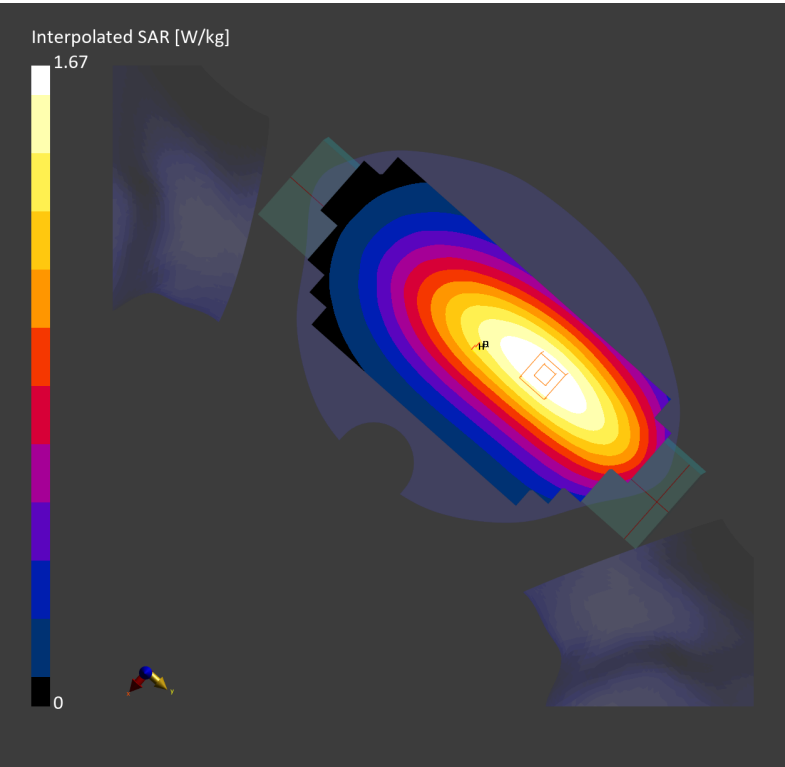
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06, 14:38	2025-06-06, 14:45
psSAR1g [W/Kg]	1.50	1.57
psSAR10g [W/Kg]	1.09	1.16
Power Drift [dB]	-0.04	-1.98
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.5
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, FRONT, D450, CW, Channel 85 (485.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	D450	CW, 0--	485.000, 85	10.65	0.865	42.3

Hardware Setup

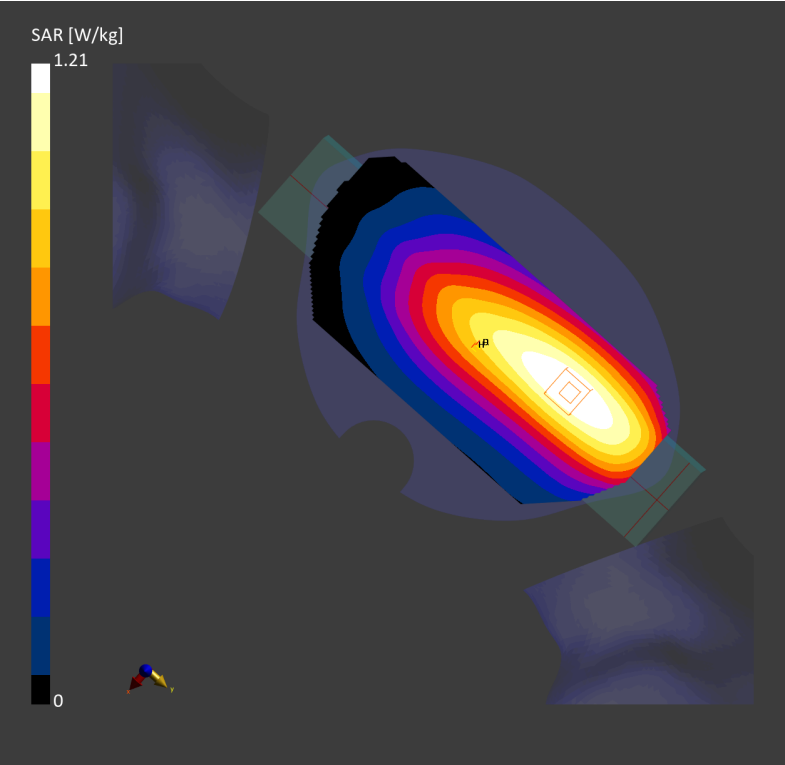
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06, 16:02	2025-06-06, 16:08
psSAR1g [W/Kg]	1.15	1.19
psSAR10g [W/Kg]	0.836	0.877
Power Drift [dB]	0.01	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.8
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, FRONT, Custom Band, CW, Channel 512000 (512.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	Custom Band	CW, 0--	512.000, 512000	10.65	0.889	41.6

Hardware Setup

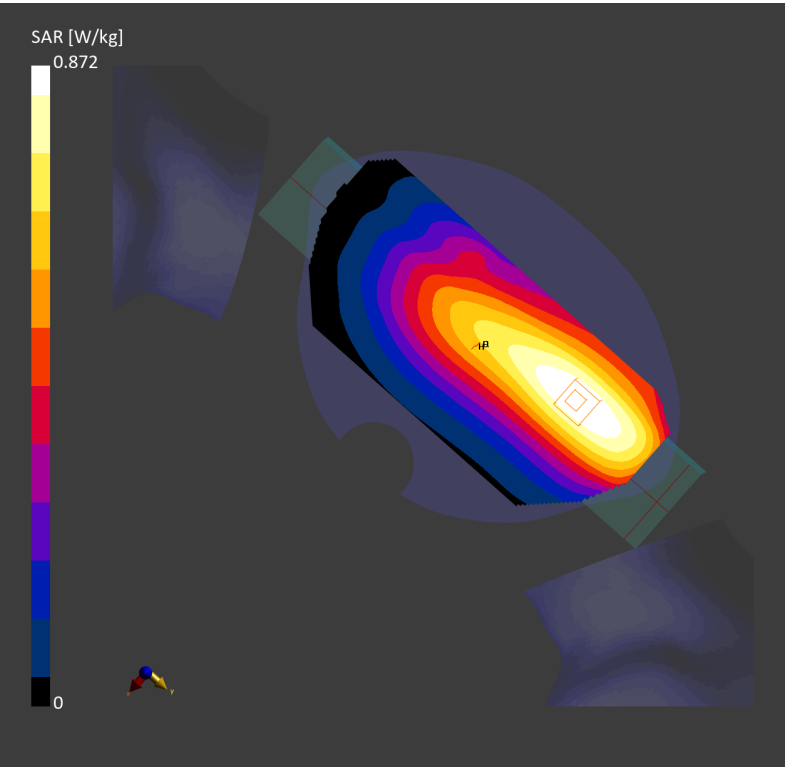
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06, 16:42	2025-06-06, 17:00
psSAR1g [W/Kg]	0.978	1.02
psSAR10g [W/Kg]	0.694	0.694
Power Drift [dB]	0.00	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.8
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, FRONT, D400, CW, Channel 100 (450.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	D400	CW, 0--	450.000, 100	10.65	0.833	43.2

Hardware Setup

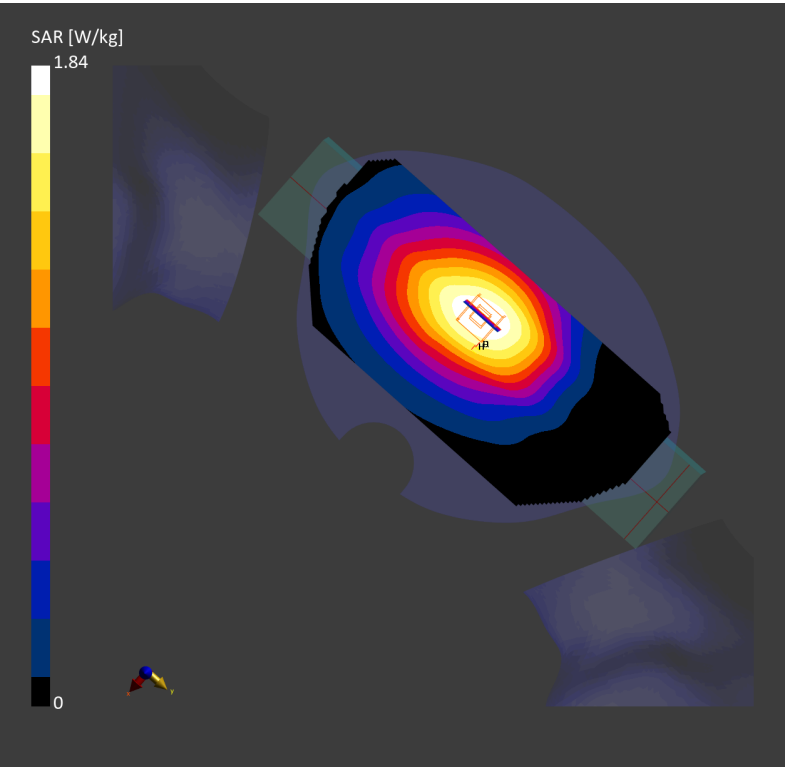
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06, 14:51	2025-06-06, 15:03
psSAR1g [W/Kg]	4.51	2.88
psSAR10g [W/Kg]	2.84	2.12
Power Drift [dB]	1.96	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.8
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, FRONT, D400, CW, Channel 100 (450.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	D400	CW, 0--	450.000, 100	10.65	0.833	43.2

Hardware Setup

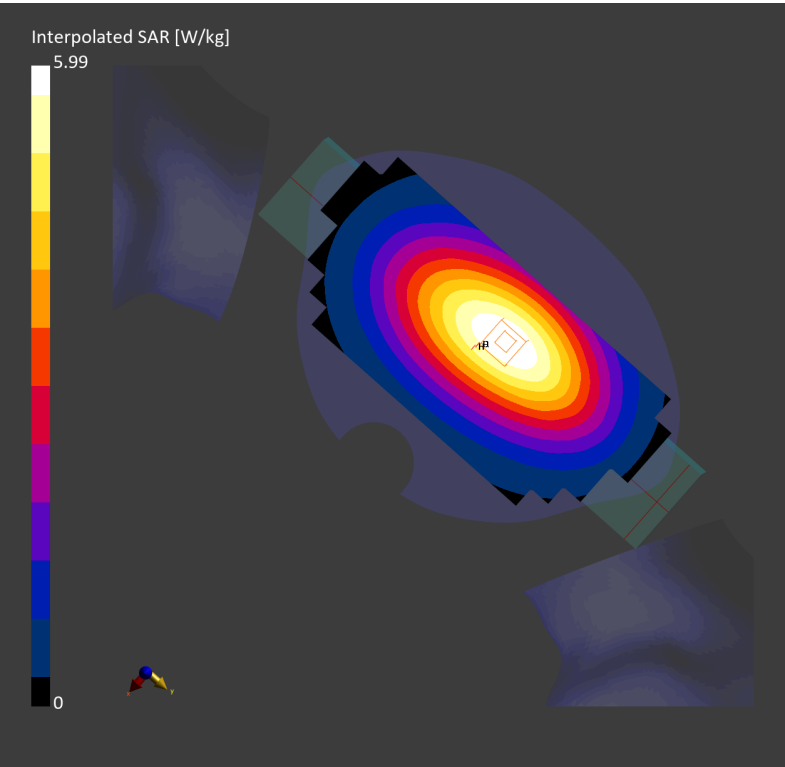
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06, 15:16	2025-06-06, 15:22
psSAR1g [W/Kg]	5.36	5.63
psSAR10g [W/Kg]	3.92	4.20
Power Drift [dB]	-0.01	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.0
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, FRONT, D400, CW, Channel 100 (450.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	D400	CW, 0--	450.000, 100	10.65	0.801	42.3

Hardware Setup

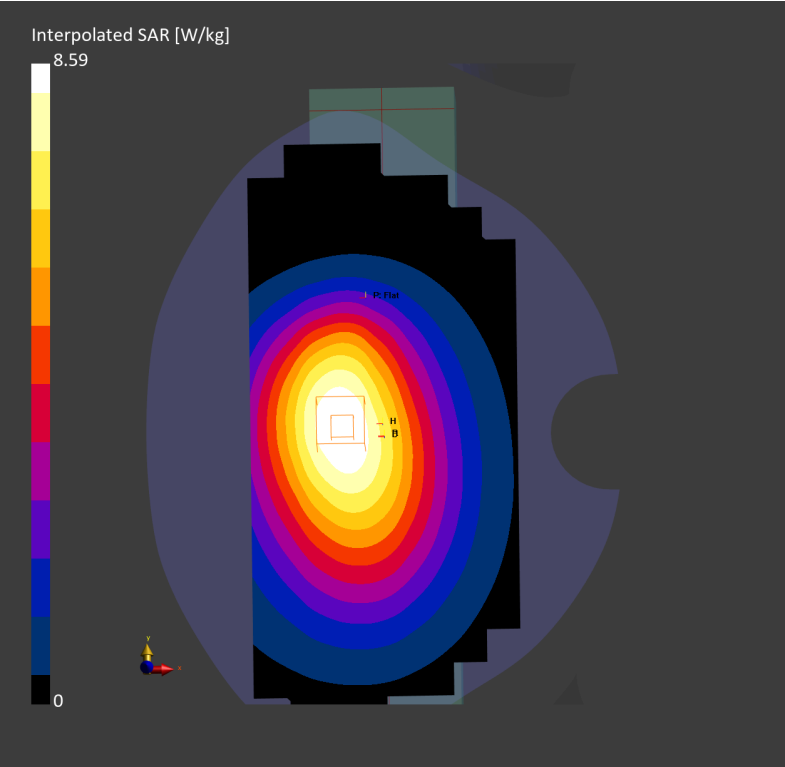
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-09	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-09, 10:07	2025-06-09, 10:14
psSAR1g [W/Kg]	7.69	8.13
psSAR10g [W/Kg]	5.59	5.89
Power Drift [dB]	0.02	-1.74
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.2
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, FRONT, D450, CW, Channel 85 (485.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	D450	CW, 0--	485.000, 85	10.65	0.865	42.3

Hardware Setup

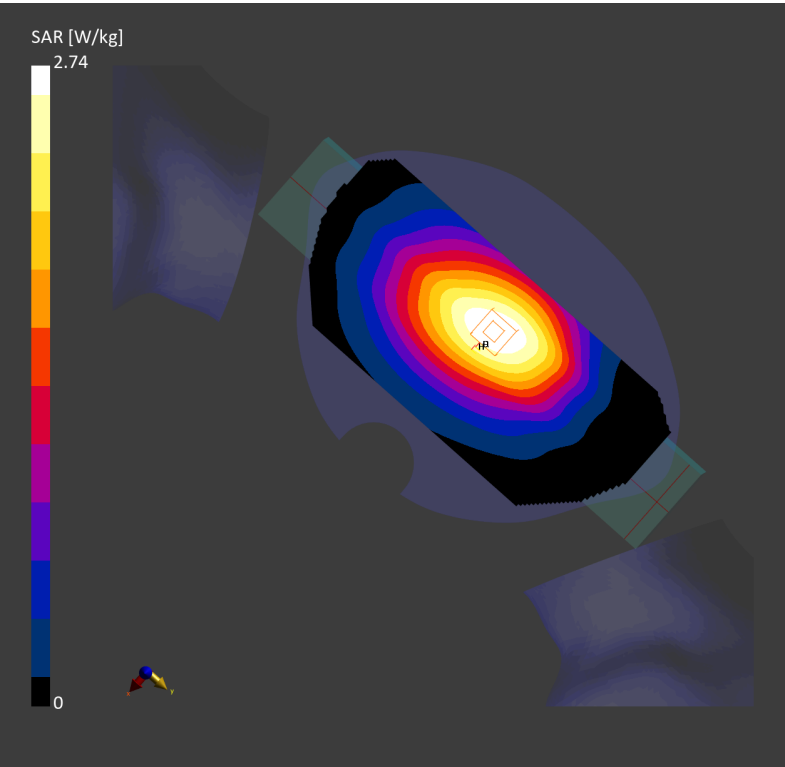
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06, 16:14	2025-06-06, 16:20
psSAR1g [W/Kg]	2.56	2.69
psSAR10g [W/Kg]	1.86	1.98
Power Drift [dB]	-0.03	-0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.5
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, FRONT, D450, CW, Channel 85 (485.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	D450	CW, 0--	485.000, 85	10.65	0.865	42.3

Hardware Setup

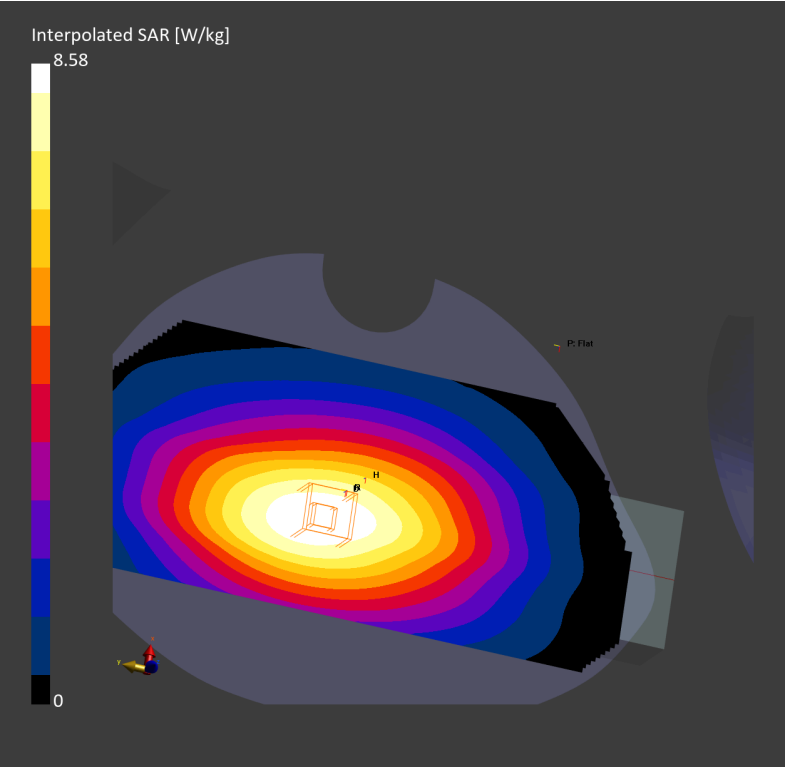
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06, 16:28	2025-06-06, 16:34
psSAR1g [W/Kg]	7.67	8.07
psSAR10g [W/Kg]	5.58	5.96
Power Drift [dB]	-0.01	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.5
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, FRONT, Custom Band, CW, Channel 512000 (512.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	Custom Band	CW, 0--	512.000, 512000	10.65	0.889	41.6

Hardware Setup

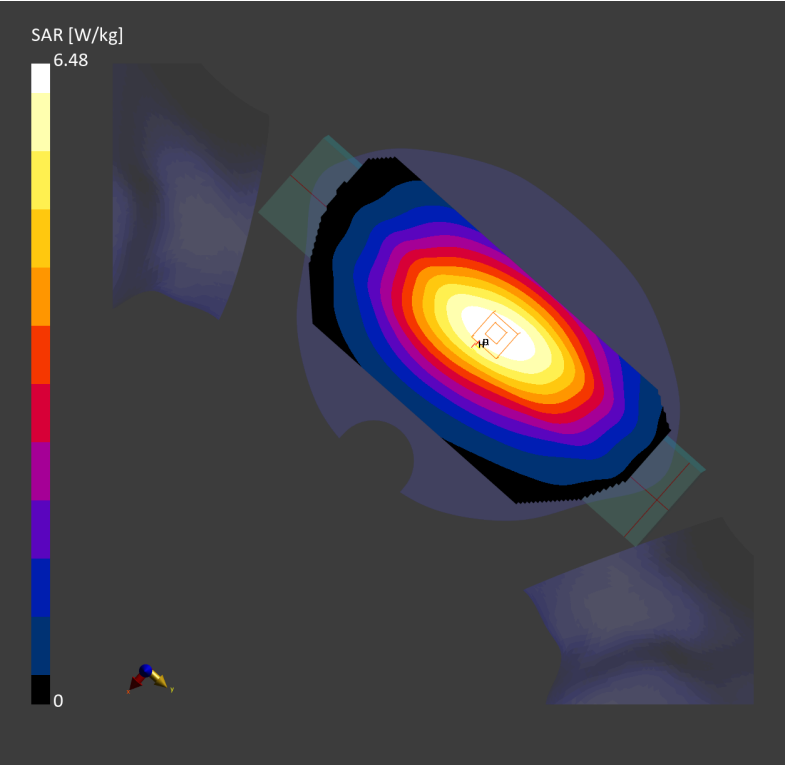
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06, 17:07	2025-06-06, 17:13
psSAR1g [W/Kg]	6.13	6.42
psSAR10g [W/Kg]	4.45	4.73
Power Drift [dB]	-0.00	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.4
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, BACK, D400, CW, Channel 100 (450.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	D400	CW, 0--	450.000, 100	10.65	0.833	43.2

Hardware Setup

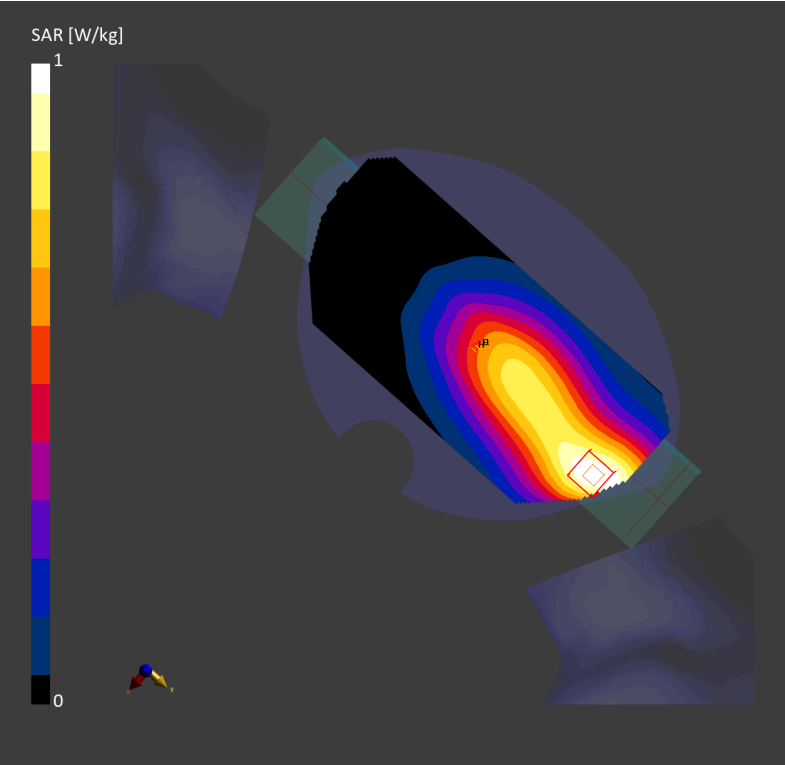
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06, 12:02	2025-06-06, 12:20
psSAR1g [W/Kg]	1.17	0.978
psSAR10g [W/Kg]	0.802	0.713
Power Drift [dB]	-0.74	-0.55
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.4
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, FRONT, D400, CW, Channel 100 (450.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	D400	CW, 0--	450.000, 100	10.65	0.801	42.3

Hardware Setup

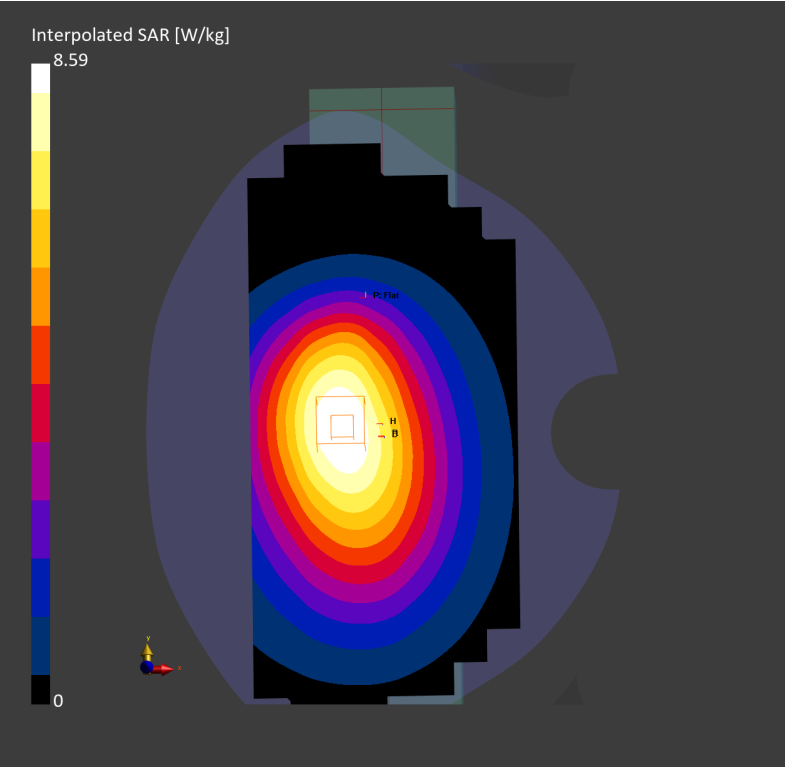
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-09	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-09, 10:07	2025-06-09, 10:14
psSAR1g [W/Kg]	7.69	8.13
psSAR10g [W/Kg]	5.59	5.89
Power Drift [dB]	0.02	-1.74
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.2
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, BACK, Custom Band, CW, Channel 512000 (512.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Custom Band	CW, 0--	512.000, 512000	10.65	0.889	41.6

Hardware Setup

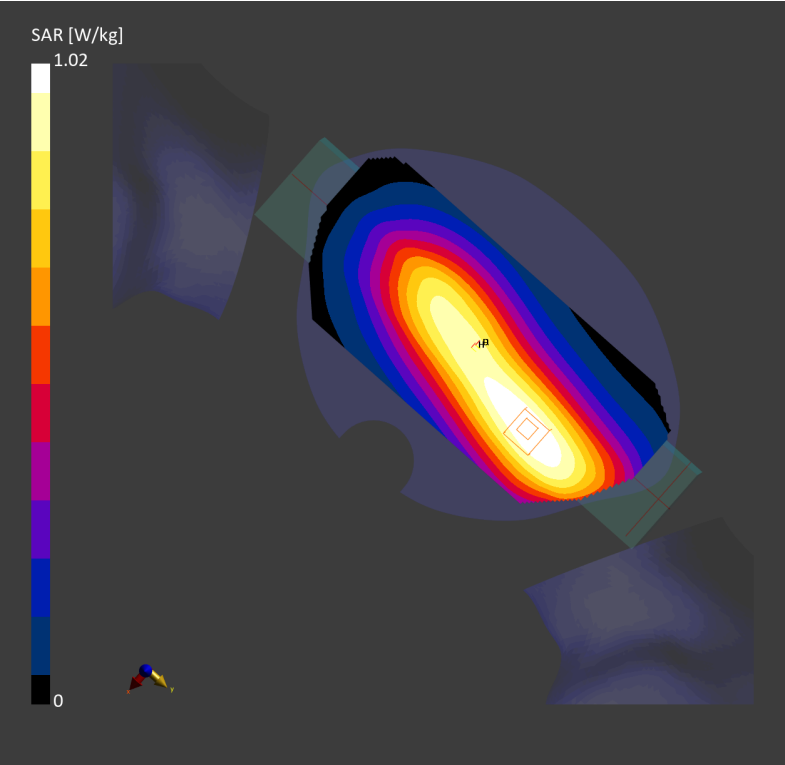
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06, 13:56	2025-06-06, 14:15
psSAR1g [W/Kg]	0.973	1.06
psSAR10g [W/Kg]	0.702	0.737
Power Drift [dB]	-1.46	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.4
Dist 3dB Peak [mm]		17.2



Measurement Report for Device, FRONT, D400, CW, Channel 100 (450.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 25.00	D400	CW, 0--	450.000, 100	10.65	0.833	43.2

Hardware Setup

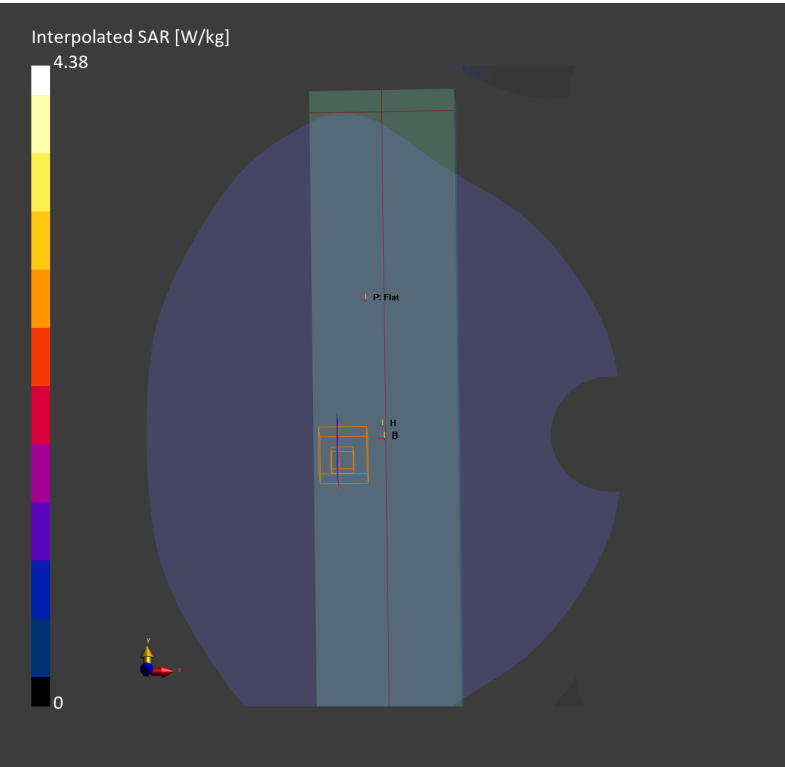
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06, 14:51	2025-06-06, 15:03
psSAR1g [W/Kg]	4.51	2.88
psSAR10g [W/Kg]	2.84	2.12
Power Drift [dB]	1.96	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.8
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, BACK, D400, CW, Channel 100 (450.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	D400	CW, 0--	450.000, 100	10.65	0.833	43.2

Hardware Setup

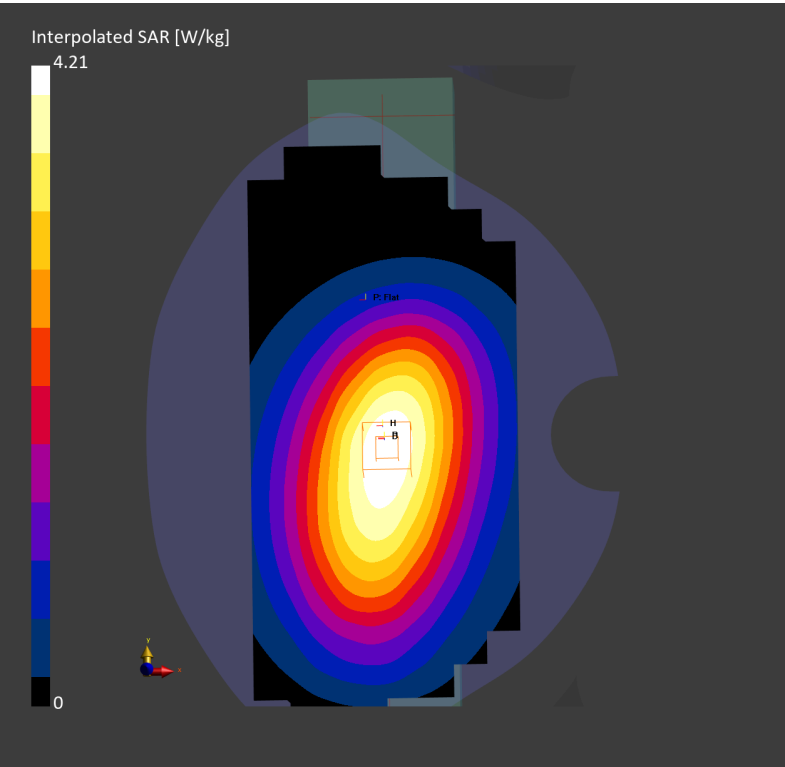
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06, 12:37	2025-06-06, 12:43
psSAR1g [W/Kg]	3.77	3.90
psSAR10g [W/Kg]	2.74	2.88
Power Drift [dB]	0.01	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.9
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, BACK, D400, CW, Channel 100 (450.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	D400	CW, 0--	450.000, 100	10.65	0.833	43.2

Hardware Setup

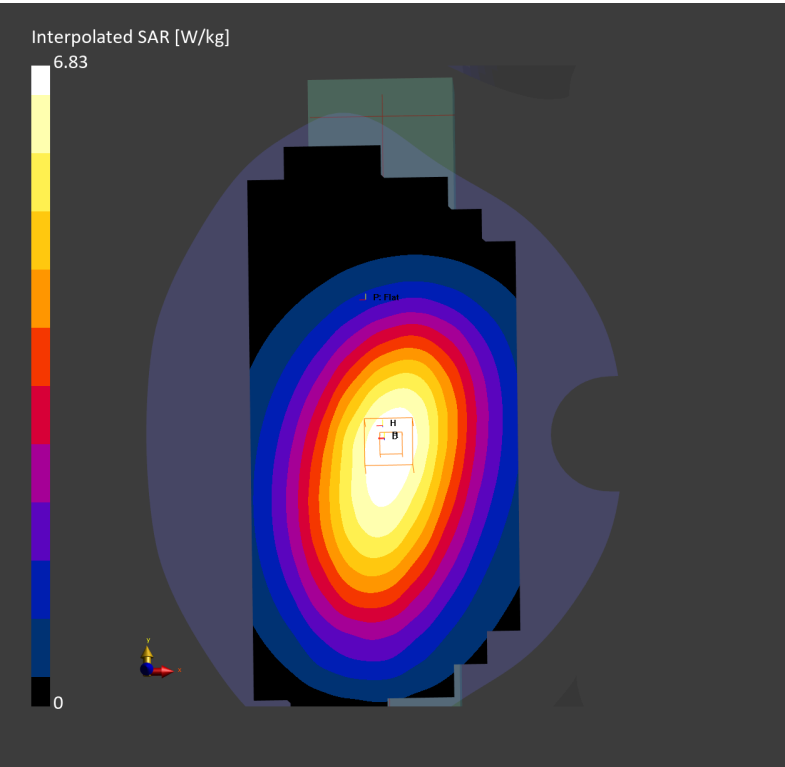
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06, 12:49	2025-06-06, 12:58
psSAR1g [W/Kg]	6.10	5.74
psSAR10g [W/Kg]	4.44	4.14
Power Drift [dB]	-0.15	1.84
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.5
Dist 3dB Peak [mm]		1.2



Measurement Report for Device, BACK, D450, CW, Channel 85 (485.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	D450	CW, 0--	485.000, 85	10.65	0.865	42.3

Hardware Setup

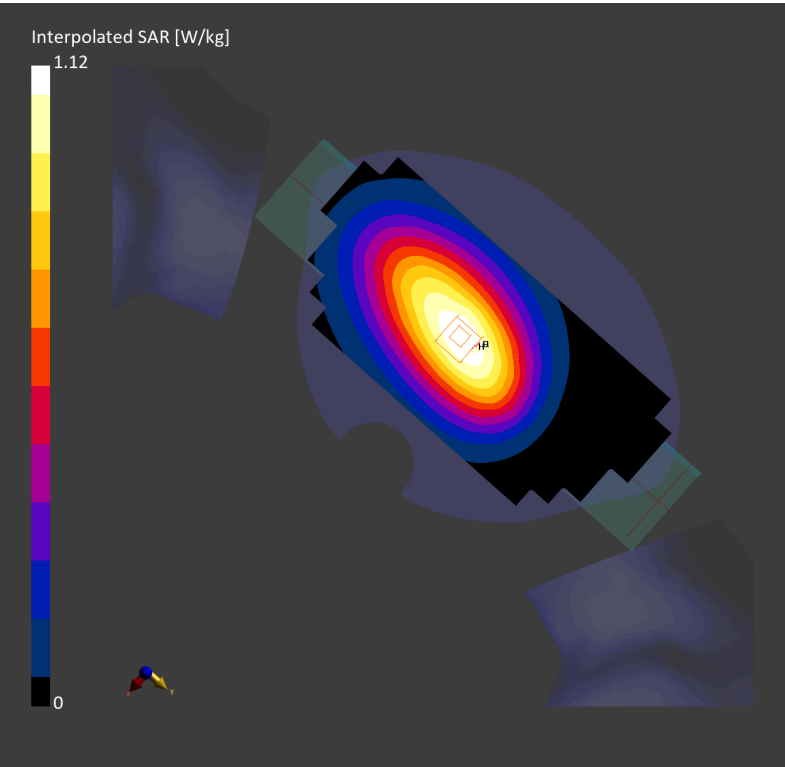
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06, 13:27	2025-06-06, 13:33
psSAR1g [W/Kg]	1.00	1.02
psSAR10g [W/Kg]	0.722	0.745
Power Drift [dB]	-0.03	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.2
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, BACK, D450, CW, Channel 85 (485.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	D450	CW, 0--	485.000, 85	10.65	0.865	42.3

Hardware Setup

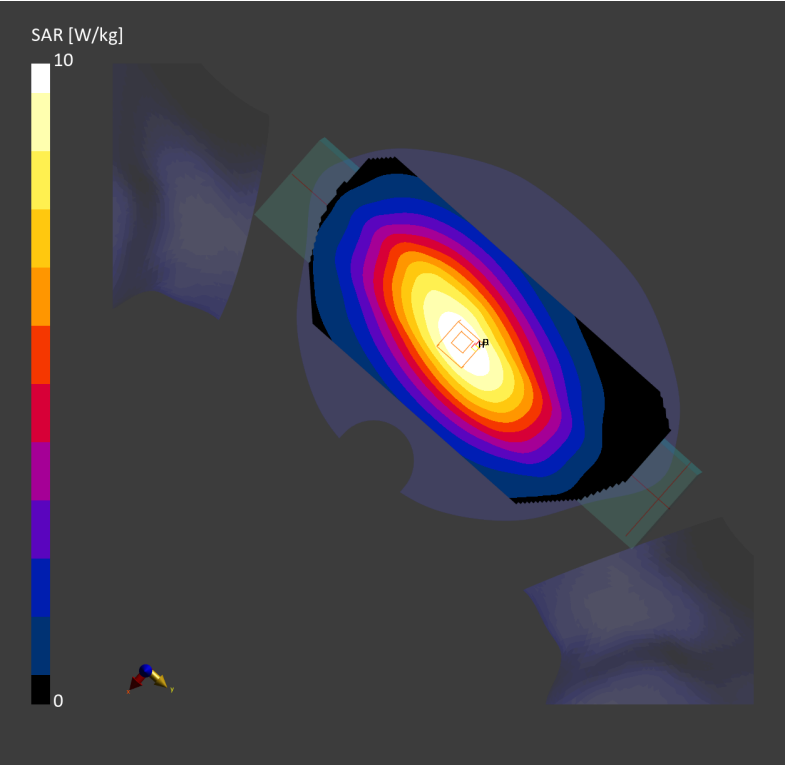
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06, 13:39	2025-06-06, 13:49
psSAR1g [W/Kg]	9.48	9.71
psSAR10g [W/Kg]	6.88	6.63
Power Drift [dB]	-0.01	-1.84
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.1
Dist 3dB Peak [mm]		16.8



Measurement Report for Device, BACK, Custom Band, CW, Channel 512000 (512.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	330.0 x 65.0 x 35.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Custom Band	CW, 0--	512.000, 512000	10.65	0.889	41.6

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2186	HSL450 Charge: xxxx, 2025-06-05	EX3DV4 - SN7929, 2025-05-02	DAE4ip Sn1907, 2025-05-05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 360.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-06-06, 14:21	2025-06-06, 14:27
psSAR1g [W/Kg]	7.90	8.17
psSAR10g [W/Kg]	5.71	5.97
Power Drift [dB]	0.01	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.1
Dist 3dB Peak [mm]		> 15.0

